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   Sommario/riassunto   International Test Conference, the cornerstone of TestWeek events, is the world s premier conference dedicated to the electronic test of devices, boards and systems covering the complete cycle from design verification, test, diagnosis, failure analysis and back to process and design improvement At ITC, test and design professionals can confront the challenges the industry faces, and learn how these challenges are being addressed by the combined efforts of academia, design tool and equipment suppliers, designers, and test engineers.